Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/637,457	ESHUN ET AL.
Examiner	Art Unit
Quynh H. Nguyen	2614

SEARCHED					
Class	Subclass	Date	Examiner		
379	15.03 202.12	7/10/2007	QN		
			-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
searched: East, USPGPub, USPAT, EPO, JPO	7/10/2007	QN
Inventor searched in PALM database	7/10/2007	QN
40		